

# Spectroscopical Study of Amorphous AsSe : Sn Films

Iovu M. S., Syrbu N. N., Shutov S. D., Vasiliev I. A., Rebeja S., Colomeico E., Popescu M., Sava, F.

[https://doi.org/10.1002/\(SICI\)1521-396X\(199910\)175:2<615::AID-PSSA615>3.0.CO;2-N](https://doi.org/10.1002/(SICI)1521-396X(199910)175:2<615::AID-PSSA615>3.0.CO;2-N)

## Abstract

The effect of tin impurities on optical spectra of thermally deposited AsSe films doped with Sn (1 to 10 at %) was studied in a wide energy interval from 0.8 to 6.2 eV by combination of reflection, absorption, photoresponse and phot capacitance spectroscopies. Most changes have been detected at the fundamental absorption edge over which a correlation between the band tail width and optical gap is demonstrated for various tin concentrations. The tin induced absorption band associated with a localized energy level at about 1.6 eV in the gap was revealed. Distinct variations in the reflectivity spectra of the fundamental absorption region suggest a tin assistance in the formation of the valence band states of the material.